

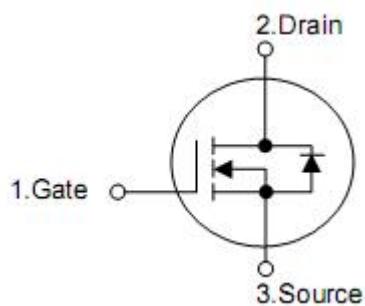
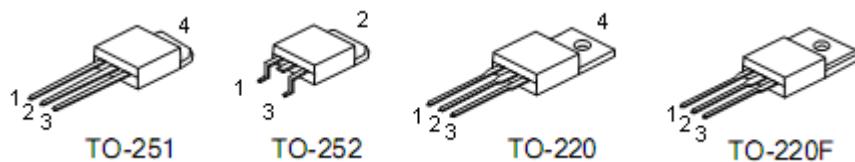
## 1. Description

The KIA2N60H N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as switching regulators, switching converters, solenoid, motor drivers, relay drivers.

## 2. Features

- $R_{DS(ON)}=4.1\Omega @ V_{GS}=10V$ .
- Low gate charge (typical 9nC)
- High ruggedness
- Fast switching capability
- Avalanche energy specified
- Improved dv/dt capability

## 3. Pin configuration



Pin	Function
1	Gate
2	Drain
3	Source
4	Drain



#### 4. Absolute maximum ratings

Parameter		Symbol	Rating			Units
			252/251	220	220F	
Drain-source voltage		V <sub>DSS</sub>		600		V
Gate-source voltage		V <sub>GSS</sub>		±30		V
Drain current continuous	T <sub>C</sub> =25°C	I <sub>D</sub>	2.0*	2.0	2.0*	A
	T <sub>C</sub> =100°C		1.35*	1.35	1.35*	A
Drain current pulsed (note1)		I <sub>DP</sub>	8*	8	8*	A
Avalanche Enlsed	Repetitive (note1)	E <sub>AR</sub>		4.4		mJ
	Single pulse (note2)	E <sub>AS</sub>		120		mJ
Peak diode recovery dv/dt (note3)		dv/dt		4.5		V/ns
Total power dissipation	T <sub>C</sub> =25°C	P <sub>D</sub>	44	55.5	23.6	W
	Derate above 25°C		0.35	0.44	0.19	W/ °C
Junction temperature		T <sub>J</sub>		+150		°C
Storage temperature		T <sub>STG</sub>		-50~+150		°C

\*Drain current limited by maximum junction temperature.

#### 5. Thermal characteristics

Parameter	Symbol	Rating			Unit
		252/251	220	220F	
Thermal resistance,Junction-ambient	R <sub>thJA</sub>	62.5	62.5	62.5	°C/W
Thermal resistance,case-to-sink typ.	R <sub>thCS</sub>	--	0.5	--	°C/W
Thermal resistance,Junction-case	R <sub>thJC</sub>	2.87	2.25	5.3	°C/W

## 6. Electrical characteristics

( $T_C = 25^\circ\text{C}$ , unless otherwise noted)

Parameter	Symbol	Test conditions	Min	Typ	Max	Unit
Off characteristics						
Drain-source breakdown voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	600	-	-	V
Zero gate voltage drain current	$I_{\text{DSS}}$	$V_{\text{DS}}=600\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$
		$V_{\text{DS}}=480\text{V}, T_C=125^\circ\text{C}$	-	-	10	$\mu\text{A}$
Gate-body leakage current	$I_{\text{GSS}}$	$V_{\text{GS}}=30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	100	nA
		$V_{\text{GS}}=-30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	-100	nA
Breakdown voltage temperature coefficient	$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	$I_{\text{D}}=250\mu\text{A}$	-	0.7	-	V/°C
On characteristics						
Gate threshold voltage	$V_{\text{GS(TH)}}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.0	-	4.0	V
Static drain-source on-resistance	$R_{\text{DS(ON)}}$	$V_{\text{DS}}=10\text{V}, I_{\text{D}}=1.0\text{A}$	-	4.1	5.0	$\Omega$
Dynamic characteristics						
Input capacitance	$C_{\text{ISS}}$	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	200	-	pF
Output capacitance	$C_{\text{OSS}}$		-	20	-	pF
Reverse transfer capacitance	$C_{\text{RSS}}$		-	4	-	pF
Switching characteristics						
Turn-on delay time	$t_{\text{D(ON)}}$	$V_{\text{DD}}=300\text{V}, I_{\text{D}}=2.0\text{A}, R_{\text{G}}=25\Omega$ (note4,5)	-	10	-	ns
Rise time	$t_R$		-	25	-	ns
Turn-off delay time	$t_{\text{D(OFF)}}$		-	25	-	ns
Fall time	$t_F$		-	30	-	ns
Total gate charge	$Q_G$	$V_{\text{DS}}=480\text{V}, I_{\text{D}}=2.0\text{A}$ $V_{\text{GS}}=10\text{V}$ (note4,5)	-	9	-	nC
Gate-source charge	$Q_{\text{GS}}$		-	1.5	-	nC
Gate-drain charge	$Q_{\text{GD}}$		-	4.0	-	nC
Drain-source diode characteristics						
drain-source diode forward voltage	$V_{\text{SD}}$	$V_{\text{GS}}=0\text{V}, I_{\text{SD}}=2.0\text{A}$	-	-	1.4	V
Continuous drain-source current	$I_{\text{SD}*}$		-	-	2.0	A
Pulsed drain-source current	$I_{\text{SM}*}$				8.0	A
Reverse recovery time	$t_{\text{RR}}$	$I_{\text{SD}}=2.0\text{A}$ $dI_{\text{SD}}/dt=100\text{A}/\mu\text{s}$ (note4)		230	-	ns
Reverse recovery charge	$Q_{\text{RR}}$			1.0	-	$\mu\text{C}$

Notes: 1.repetitive rating:pulse width limited by maximum junction temperature

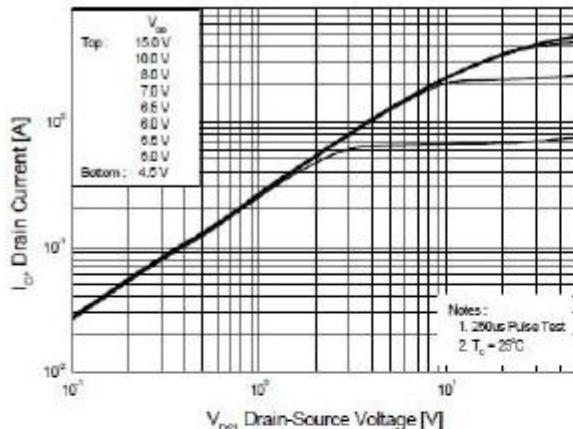
2. $L=60\text{mH}, I_{\text{AS}}=2.0\text{A}, V_{\text{DD}}=50\text{V}, R_{\text{G}}=25\Omega$ , starting  $T_J=25^\circ\text{C}$

3. $I_{\text{SD}} \leq 2.0\text{A}, dI/dt \leq 200\text{A}/\mu\text{s}, V_{\text{DD}} \leq \text{BV}_{\text{DSS}}$ , starting  $T_J=25^\circ\text{C}$

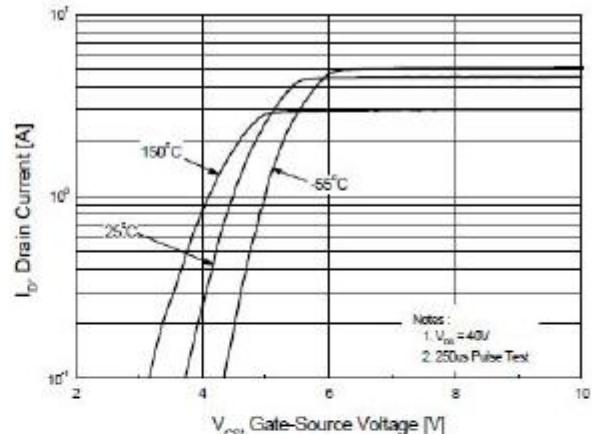
4.Pulse test:pulse width $\leq 300\mu\text{s}$ ,duty cycle $\leq 2\%$

5.Essentially independent of operating temperature

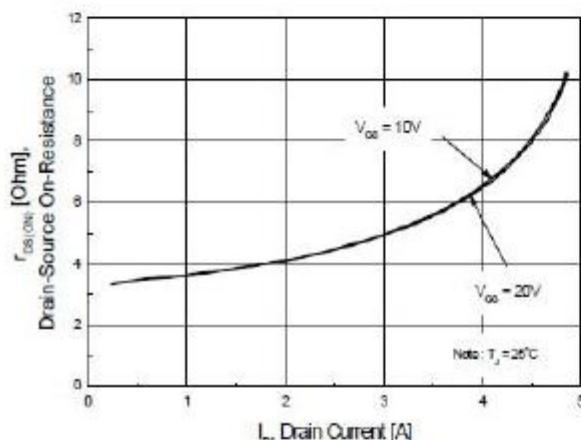
## 7. Typical characteristics



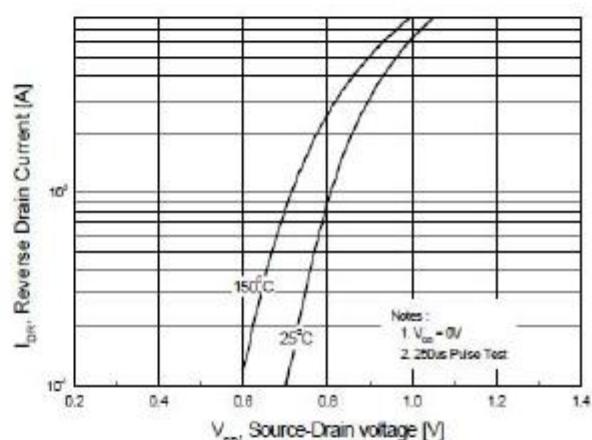
**Figure 1. On-Region Characteristics**



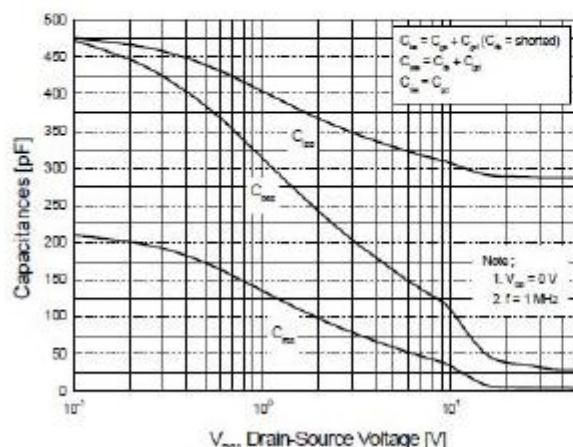
**Figure 2. Transfer Characteristics**



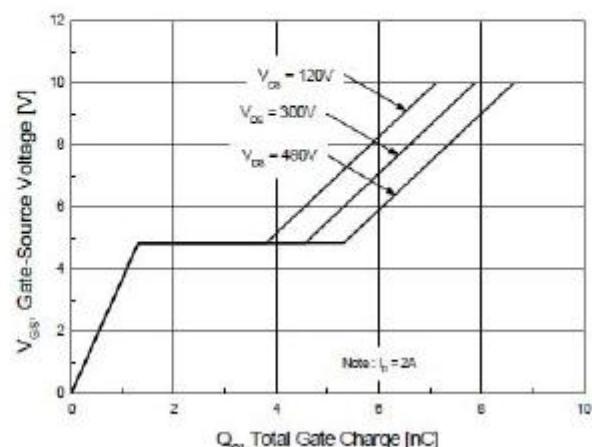
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



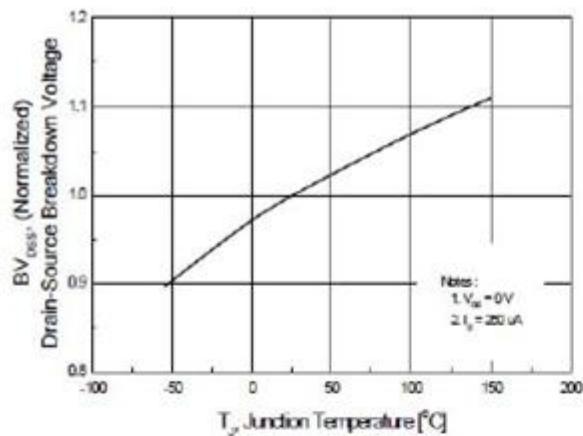
**Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature**



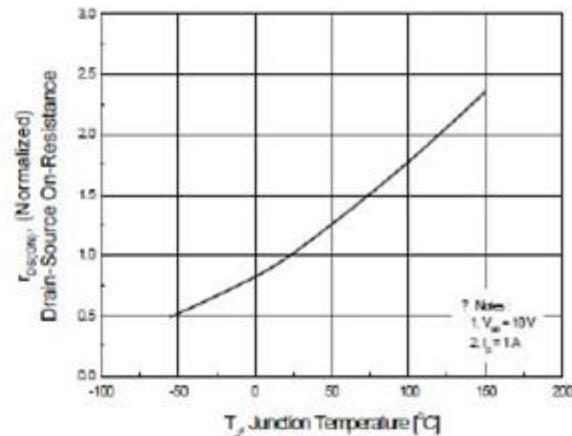
**Figure 5. Capacitance Characteristics**



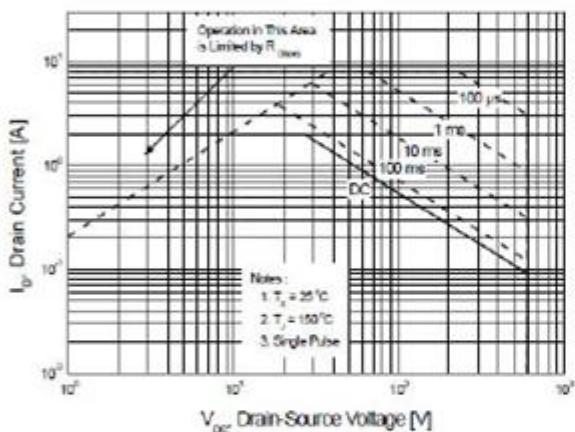
**Figure 6. Gate Charge Characteristics**



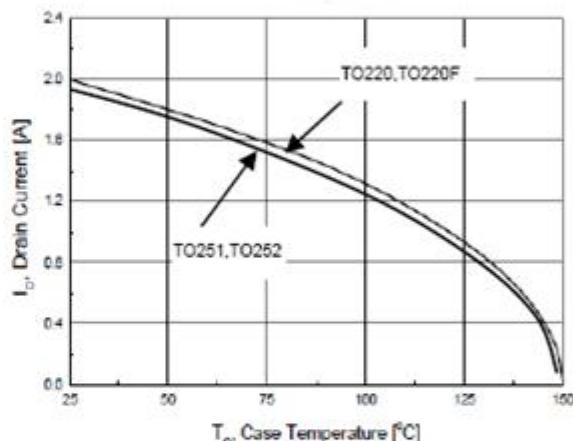
**Figure 7. Breakdown Voltage Variation  
vs Temperature**



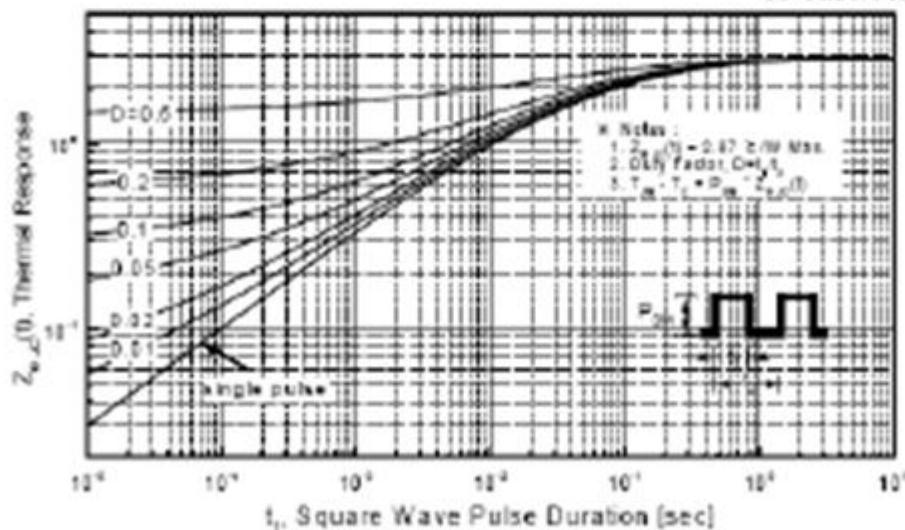
**Figure 8. On-Resistance Variation  
vs Temperature**



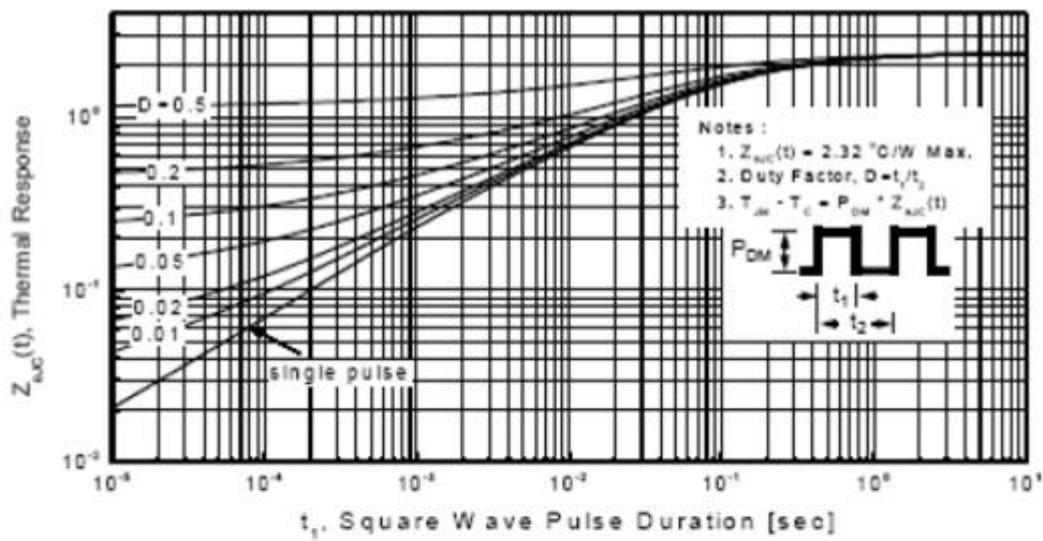
**Figure 9 . Maximum Safe Operating Area**



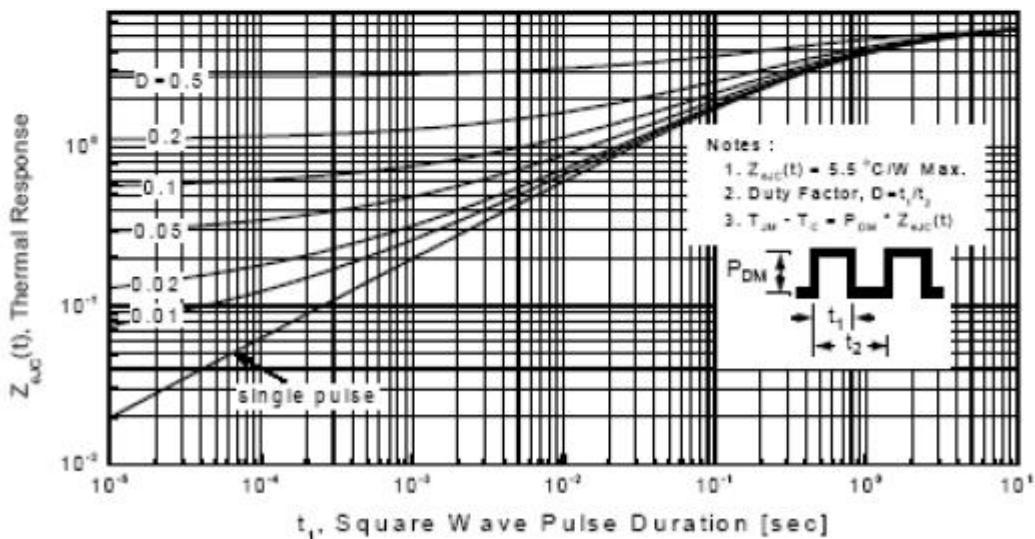
**Figure 10. Maximum Drain Current  
vs Case Temperature**



**Figure 11. Transient Thermal Response Curve  
for TO-251/252**



**Figure 11-1. Transient Thermal Response Curve  
for TO-220**



**Figure 11-2. Transient Thermal Response Curve  
for TO-220F**